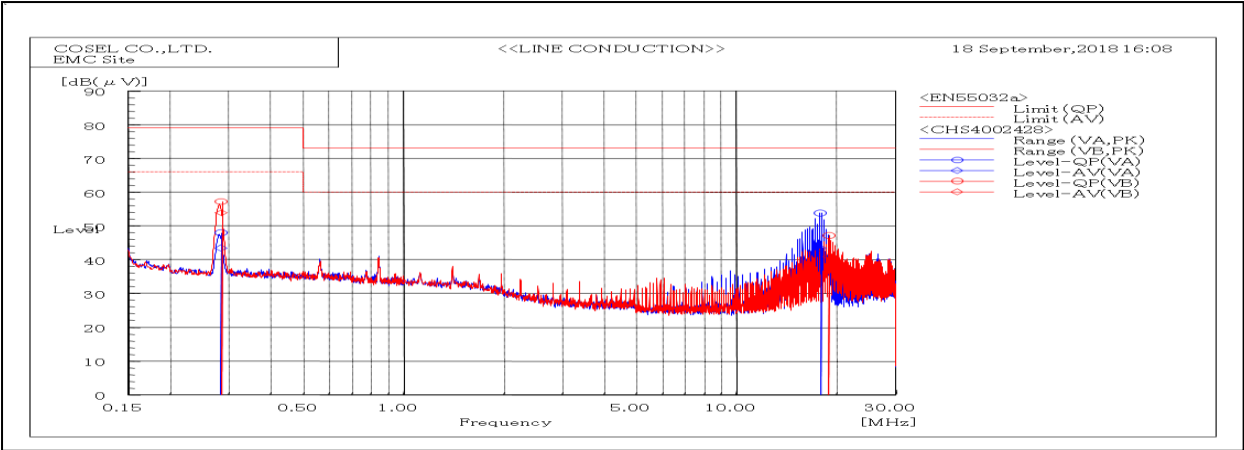
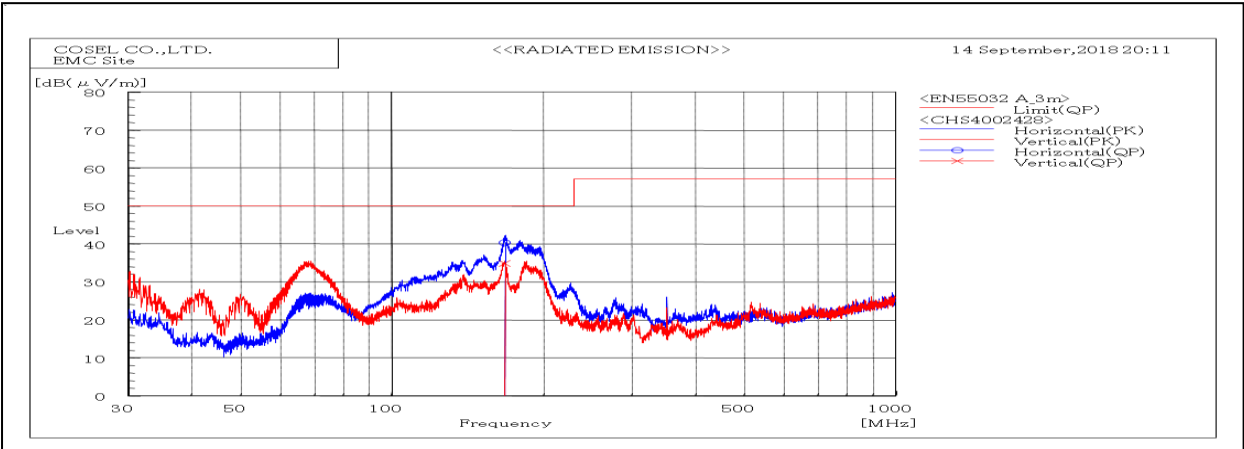


DATA SHEET		Date	27-Sep-18
Model	CHS4002428	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa



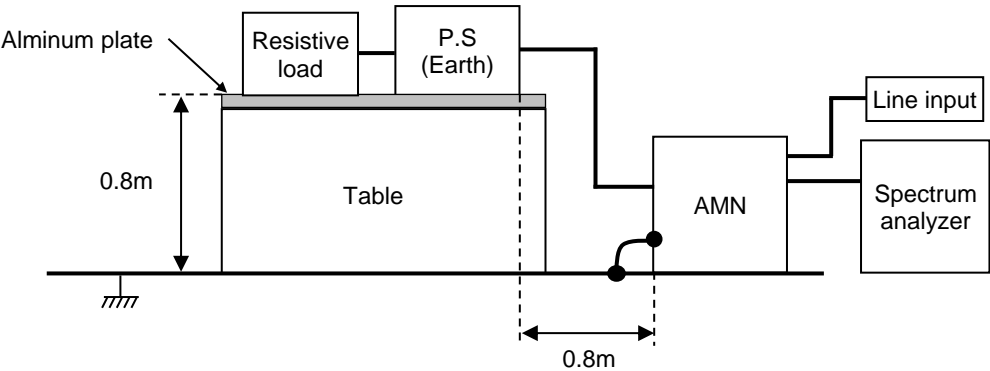
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.28444	VA	48	43.4	79	66	31	22.6	Pass	
0.2851	VB	57.2	53.9	79	66	21.8	12.1	Pass	
17.89115	VA	53.8	43.4	73	60	19.2	16.6	Pass	
18.97235	VB	47.2	40.9	73	60	25.8	19.1	Pass	



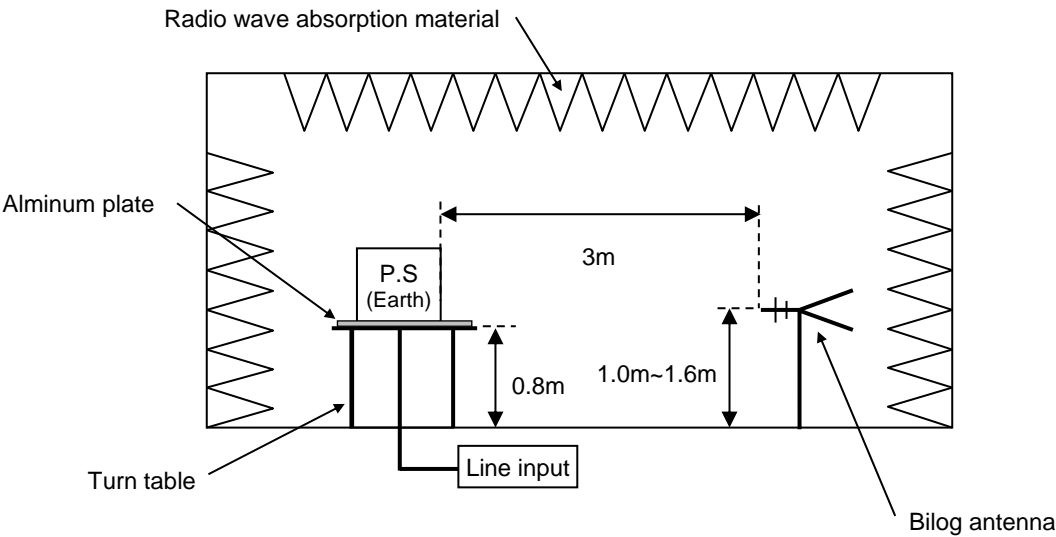
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
167.652	V	Stable	34.8	50.0	15.2	Pass	101	94	
167.778	H	Stable	40.3	50.0	9.7	Pass	145	314	

DATA SHEET		Date	27-Sep-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Nakagawa

1. Line conduction



2. Radiated emission

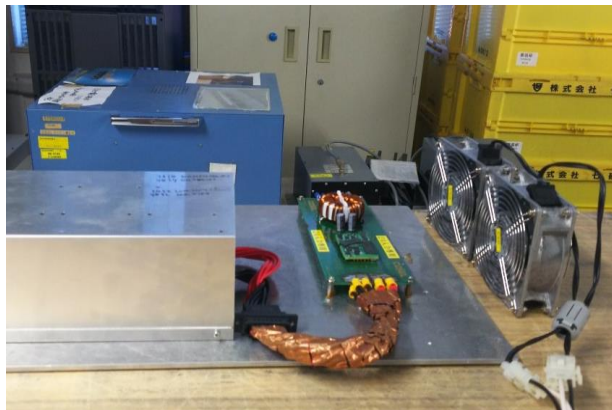


## Conditions

Test : EMI  
Model Name : CHS40024□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

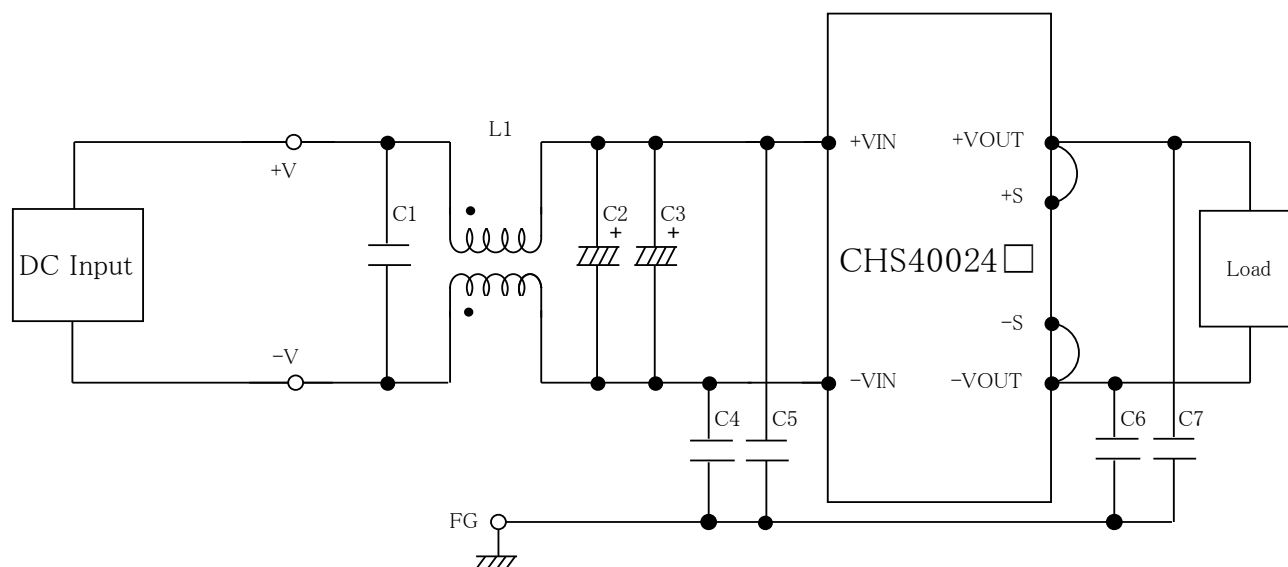


Fig.1 Testing circuitry

L1 : 1mH SC-30-100 (TOKIN)  
C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)  
C2,C3 : 50V 330  $\mu$ F PWseries (nichicon)  
C4,C5 : 630V 0.068  $\mu$ F FPD22J683J4 (NITSUKO)  
C6,C7 : 630V 0.033  $\mu$ F FPD22J333J4 (NITSUKO)